

REMARKS

This amendment is submitted to correct several inadvertent errors in claim dependency and grammar in the original claims, and to add new claims 78-147 directed to microstructure plates disclosed in the application and methods for their use. Support for new claims 78-143 may be found in original claims 1-40, 51-60 and 62-77. Support for new claims 144-147 may be found in the specification at page 13, lines 19-20, and page 14, lines 11-14. No prohibited new matter has been added.


Except for issue fees payable under 37 C.F.R. §1.18, the Commissioner is hereby authorized by this paper to charge any additional fees during the entire pendency of this application including fees due under 37 C.F.R. § 1.16 and 1.17 which may be required, including any required extension of time fees, or credit any overpayment to Deposit Account No. 50-0310. This paragraph is intended to be a **CONSTRUCTIVE PETITION FOR EXTENSION OF TIME** in accordance with 37 C.F.R. § 1.136(a)(3).

Respectfully submitted,

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APPENDIX

The following amendments were entered above:

IN THE CLAIMS:

The claims were amended as follows:

18. (Amended) The system of claim [17] 13, wherein the capture matrix binds the molecule of interest non-specifically.
19. (Amended) The system of claim 18 wherein the capture matrix comprises a material selected from the group consisting of metal chelate resins, anionic resins, cationic resins, polyvinylidene fluoride, nitrocellulose and [positively] charged nylon.
30. (Amended) The system of claim [20] 26 wherein at least one layer is formed from a self-sealing material.
32. (Amended) The system of claim [20] 26, wherein at least one layer is formed from polytetrafluoroethylene.
62. (Amended) The method of claim 51 wherein the electrode assembly is in place when the sample is loaded into the sample-accepting microstructure section in step [(c)] (b).

69. (Amended) The method of claim 51 wherein the detection in step (e) is by a method selected from the group consisting of fluorometry, colorimetry, luminometry, mass spectrometry, electrochemical detection, and radioactivity detection.